WHAT IS CLAIMED IS:

1. A probe card used for performing an electrical test of a subject to be tested that is a semiconductor device or the like and comprising a substrate body, a contactor unit provided at one side of the substrate body for establishing an electrical contact with the subject to be tested as well as for establishing an electrical contact with the substrate body via an interposer, supporting means for supporting one side of the contactor unit with elastic force and a parallelism adjusting means that comes in contact with the other side of the contactor unit in a vertical direction for adjusting a parallelism of the contactor unit, wherein the supporting means is configured to include a support member arranged at one side of the substrate body and a coil spring interposed toward a vertical direction between a flange section provided at an inside section of the support member and a flange section provided at an outside section of the contactor unit.

2. The probe card claimed in Claim 1, wherein a first reinforcing plate that comes in contact with the substrate body is arranged at the other side of the substrate body.

3. The probe card claimed in Claim 2, wherein the support member is attached to the first reinforcing plate via a spacer inserted into a bore hole formed on the substrate body.

4. The probe card claimed in Claim 2, wherein a heat-conductive sheet is provided between the substrate body

and the first reinforcing plate.

5. The probe card claimed in Claim 3, wherein a heat-conductive sheet is provided respectively between the substrate body and the first reinforcing plate, between the spacer and the first reinforcing plate and between the spacer and the support member.

6. The probe card claimed in any one of Claims 2 to 5, wherein a screw serving as the parallelism adjusting means is threadedly secured to the first reinforcing plate so as to cause its leading edge to be in contact with the contactor unit via a hole formed on the substrate body, while a second reinforcing plate is attached to the first reinforcing plate for covering the hole formed on the first reinforcing plate and a screw is threadedly secured to the second reinforcing plate so as to cause its leading edge to be in contact with a position of the substrate body above the contactor unit via the hole.

7. The probe card claimed in Claim 6, wherein a heat-conductive sheet is provided between the first reinforcing plate and the second reinforcing plate.